Real-time observation of surface chemical reaction at millisecond resolution by means of soft X-ray dispersive XAFS

Kenta Amemiya,¹ Yuka Kousa,² Shuichi Nakamoto,² Taiga Harada,² Shogo Kozai,² Masaaki Yoshida,² Hitoshi Abe,^{1,2} Ryohei Sumii,¹ Masako Sakamaki,¹ Kazuma Suzuki,² Hiroshi Kondoh,² Tsuneharu Koide,¹ Kenji Ito,¹ Kimichika Tsuchiya,³ Kentaro Harada,³ Hiroyuki Sasaki,³ Tomohiro Aoto,³ Tatsuro Shioya,³ Takashi Obina,³ Shigeru Yamamoto¹ and Yukinori Kobayashi³

¹Institute of Materials Structure Science, High Energy Accelerator Research Organization, 1-1 Oho, Tsukuba, 305-0801 Ibaraki, Japan ²Department of Chemistry, Faculty of Science and Technology, Keio University, 3-14-1 Hiyoshi, Kohoku-ku, 223-8522 Yokohama, Japan ³Accelerator Laboratory, High Energy Accelerator Research Organization, 1-1 Oho, Tsukuba, 305-0801 Ibaraki, Japan

A dispersive XAFS technique in the soft X-ray region has been developed, as illustrated in Fig. 1, to realize the real-time observation of surface chemical reactions at one event, and a time resolution of 33 ms [1] or faster has been achieved. The observation of the CO oxidation reaction on Ir(111) surface is shown in Fig. 2 as an example. The coverage of each species at the surface during the reaction is quantitatively estimated from a series of XAFS spectra. Moreover, the observation of the changes in the molecular orientation within one reaction has been also achieved [2] by combing the dispersive XAFS technique with polarization switching [3] between the horizontal and vertical linear polarizations.

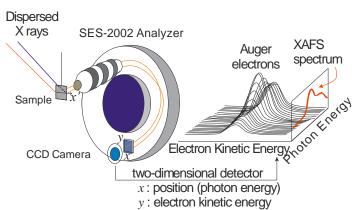


Fig. 1. Schematic layout for dispersive XAFS measurement. The position, x', on the sample surface corresponds to the photon energy. The Auger electrons emitted at x' after X-ray absorption are separately corrected at x on the two-dimensional detector, yielding the XAFS spectrum.

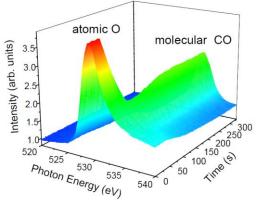


Fig. 2. Three-dimensional plot of O K-edge XAFS spectra taken at every 33 ms during the exposure of O/Ir(111) surface to 4×10^{-7} Torr CO at 400 K.

^[1] K. Amemiya et al., Appl. Phys. Lett. 99, 074104 (2011).

^[2] K. Amemiya et al., Appl. Phys. Lett. 101, 161601 (2012).

^[3] K. Amemiya et al., J. Phys.: Conf. Ser. 425, 152015 (2013).